Machine Learning Algorithms and Models for Image Processing

Guest Editor:

Dr. Satya P. Singh
Electronics and Communication
Engineering Department, Netaji
Subhas University of Technology,
Delhi 999008, India

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submissions:
closed (28 February 2023)

Message from the Guest Editor

Dear Colleagues,

This Special Issue will accept original research papers, reviews, and reports on various research progresses in machine learning and pattern recognition and the challenges experienced in numerous machine learning algorithms and pattern recognition mechanisms.

Submissions are welcome on optimizing techniques and algorithms based on conventional approaches with new machine learning techniques and mechanisms (e.g., deep learning, support vector machines, statistical methods, manifold-space-based methods, artificial neural networks, convolutional neural networks, recurrent neural networks). Potential topics include but are not limited to:

- Machine and deep learning in healthcare/medicine;
- Computer vision techniques in pattern recognition;
- Computer-aided diagnosis;
- Analyzing fMRI data using deep learning;
- Deep learning in medical science;
- Medical image reconstruction;
- Medical image retrieval.

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Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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